

Supporting Information

Dual function of precisely modified hydroxy-PS-*b*-PMMA as neutral layers and thin films for perpendicularly oriented lamella

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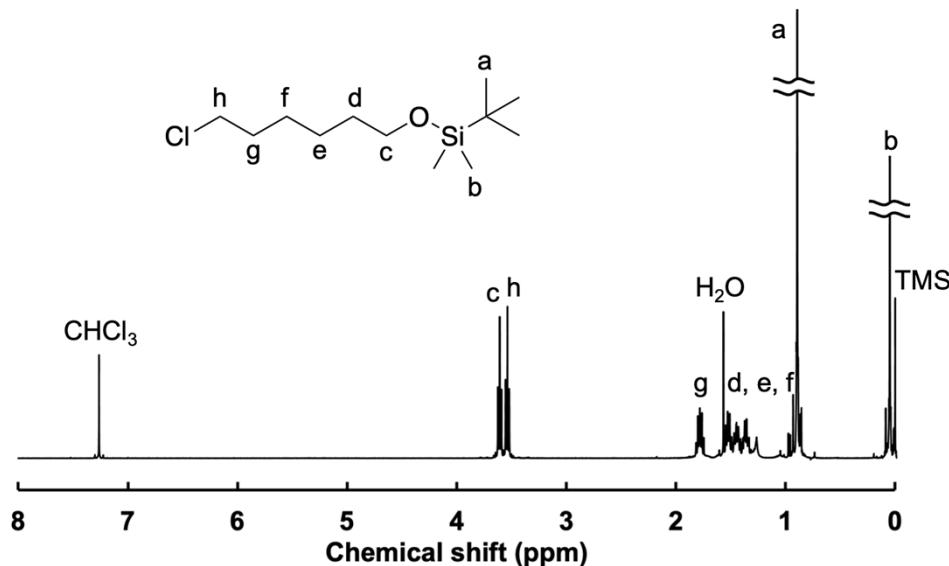


Fig. S1 ¹H NMR spectrum of ClC₆OTBS in CDCl₃.¹

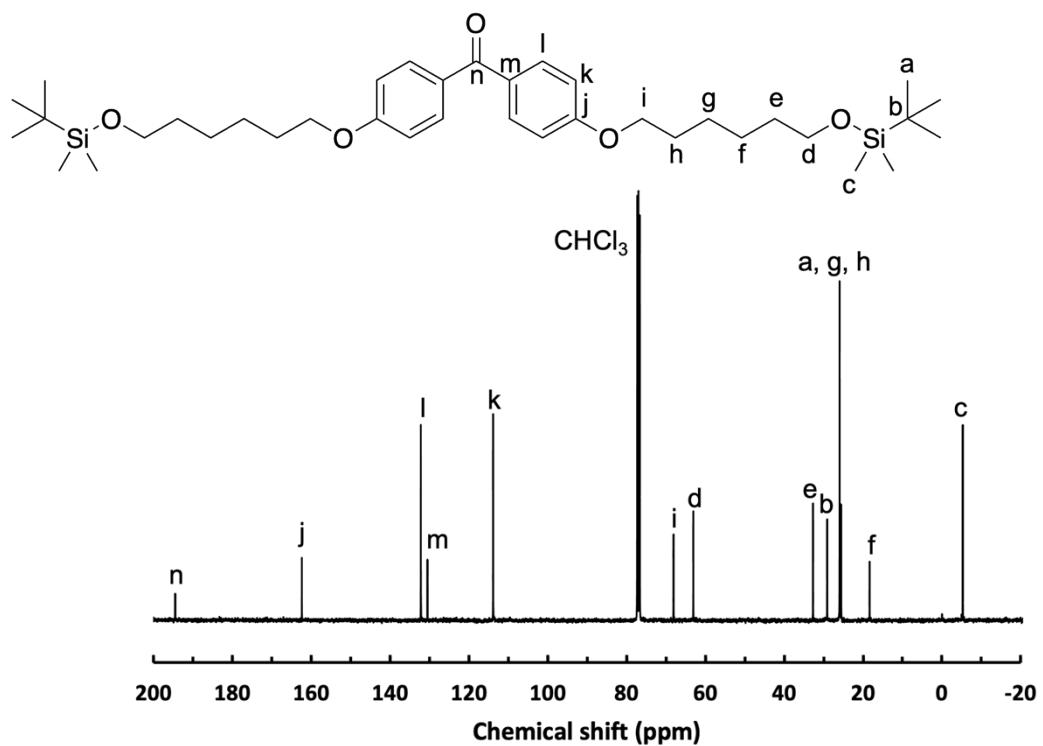


Fig. S2 ¹H NMR spectrum of BP-(OTBS)₂ in CDCl₃.

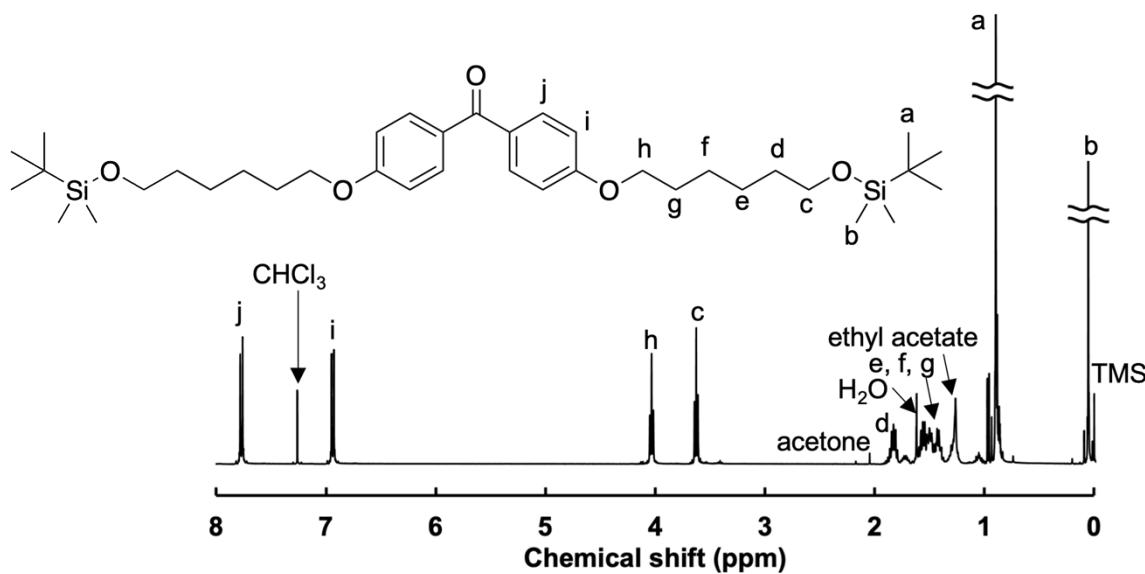


Fig. S3 ¹³C NMR spectrum of BP-(OTBS)₂ in CDCl₃.

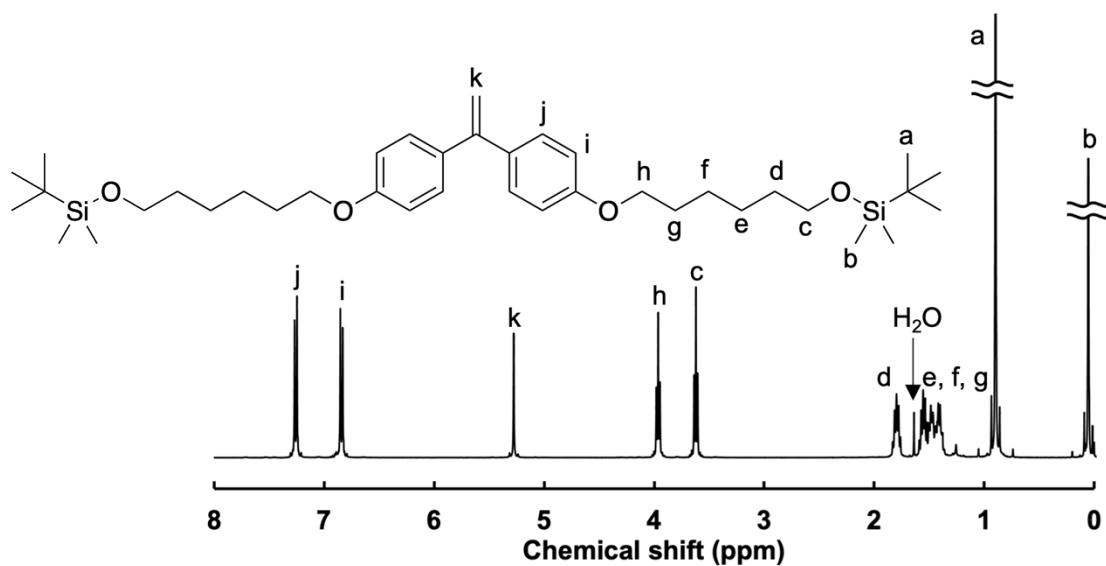


Fig. S4 ¹H NMR spectrum of DPE-(OTBS)₂ in CDCl₃.

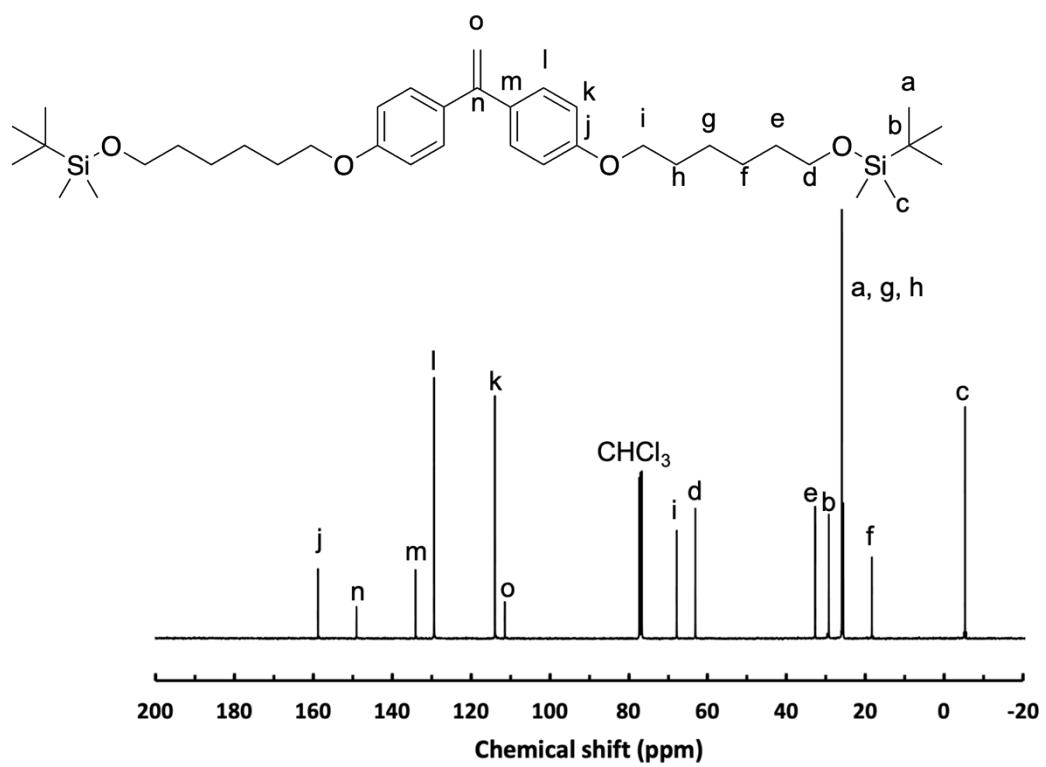


Fig. S5 ¹³C NMR spectrum of DPE-(OTBS)₂ in CDCl₃.

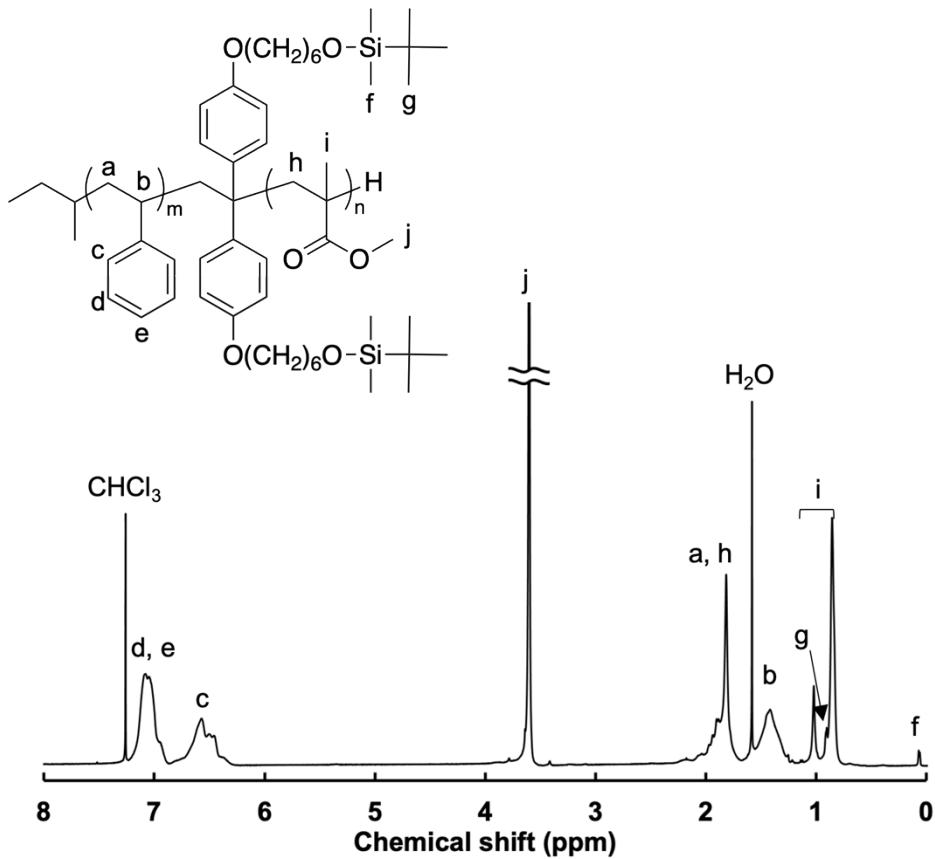


Fig. S6 ^1H NMR spectrum of PS-(OTBS)₂-PMMA in CDCl_3 without TMS.

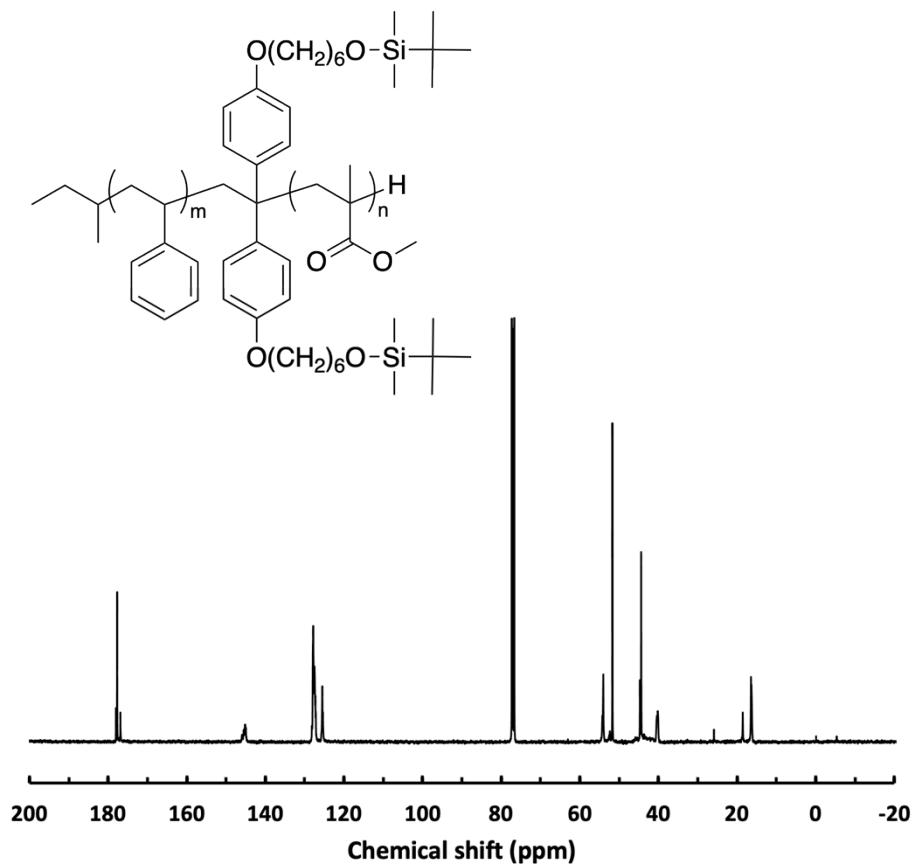


Fig. S7 ^{13}C NMR spectrum of PS-(OTBS)₂-PMMA in CDCl_3 .

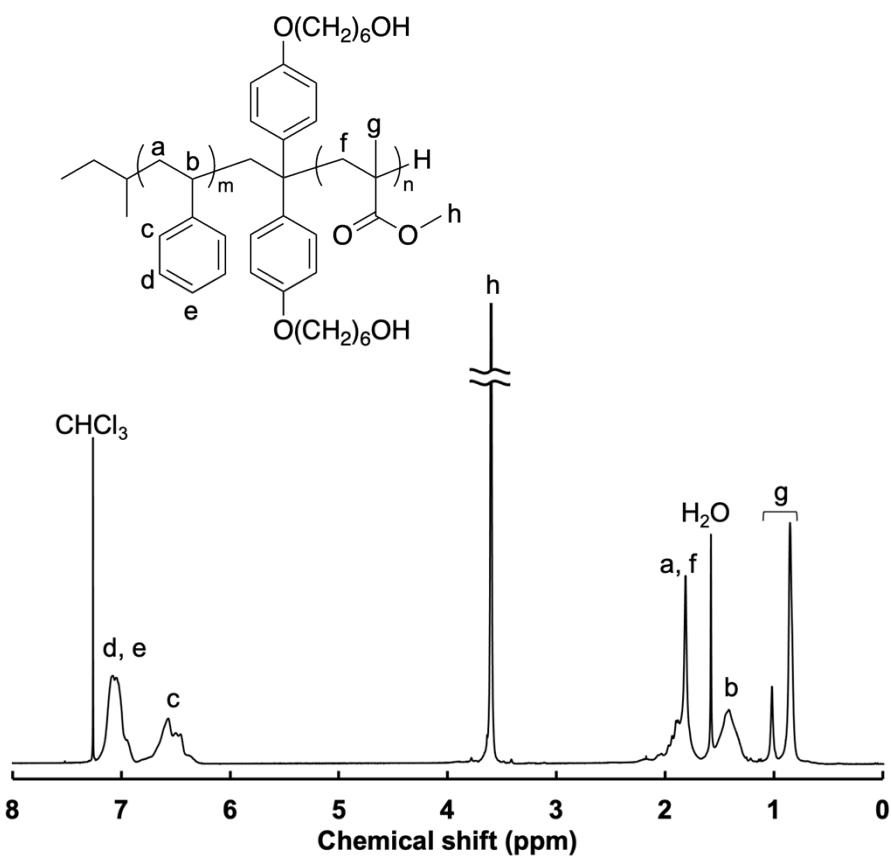


Fig. S8 ^1H NMR spectrum of PS-(OH)₂-PMMA in CDCl₃ without TMS.

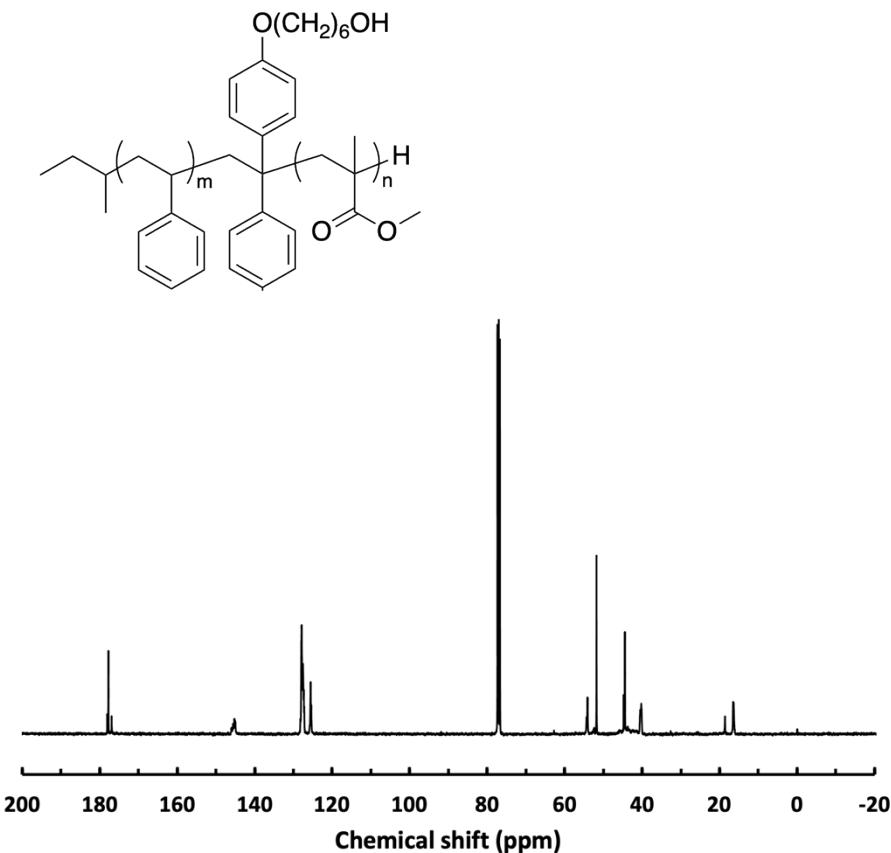


Fig. S9 ^{13}C NMR spectrum of PS-(OH)₂-PMMA in CDCl₃.

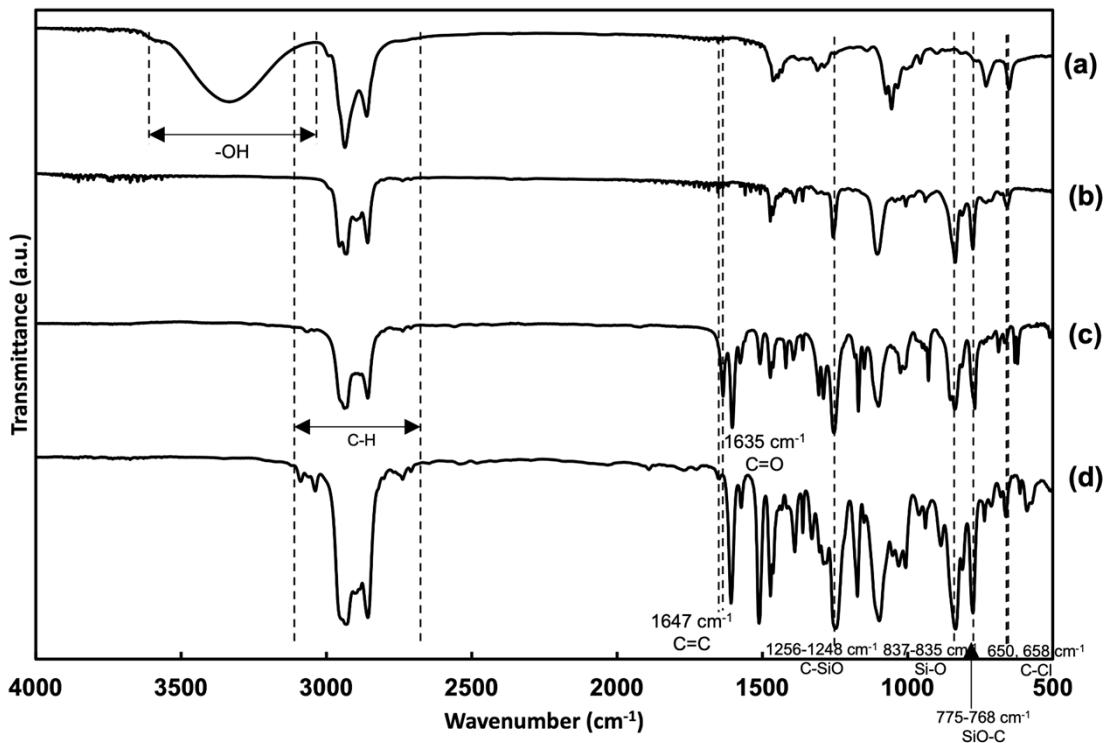


Fig. S10 FT-IR spectra of (a) 6-chloro-1-hexanol, (b) ClC_6OTBS , (c) BP-(OTBS)₂ and (d) DPE-(OTBS)₂.

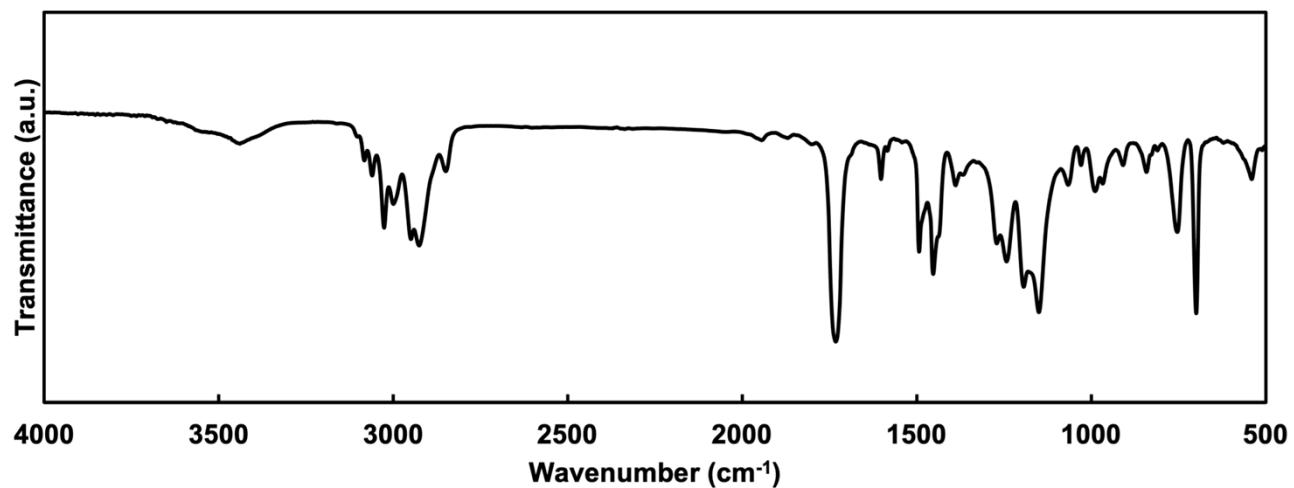


Fig. S11 FT-IR spectrum of PS-(OTBS)₂-PMMA.

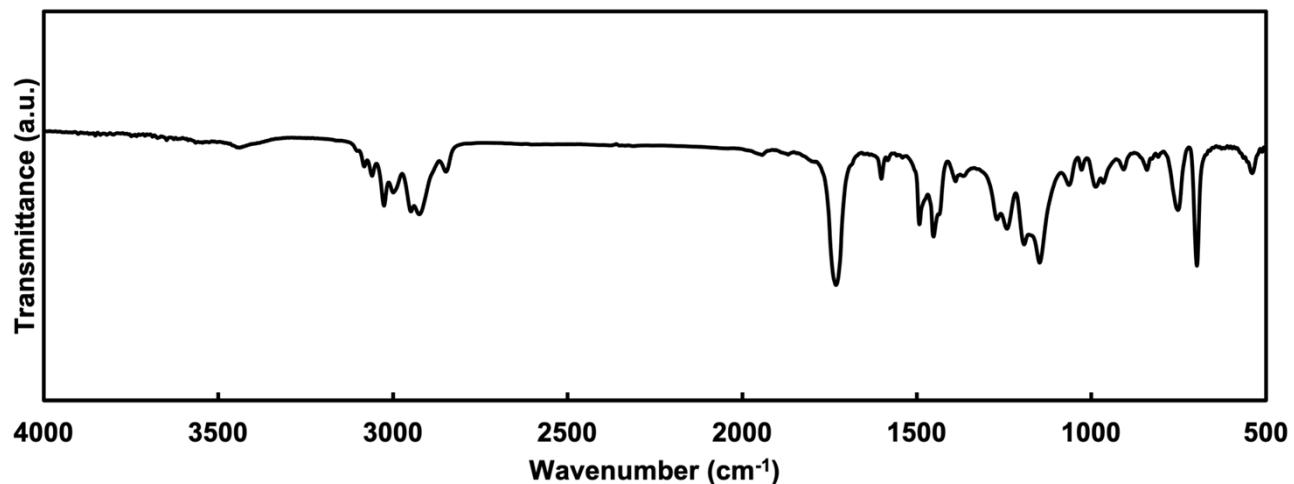


Fig. S12 FT-IR spectrum of PS-(OH)₂-PMMA.

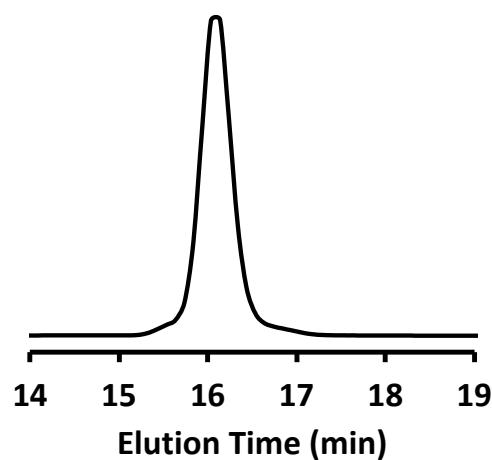


Fig. S13 SEC chromatogram of PS-(OTBS)₂-PMMA.

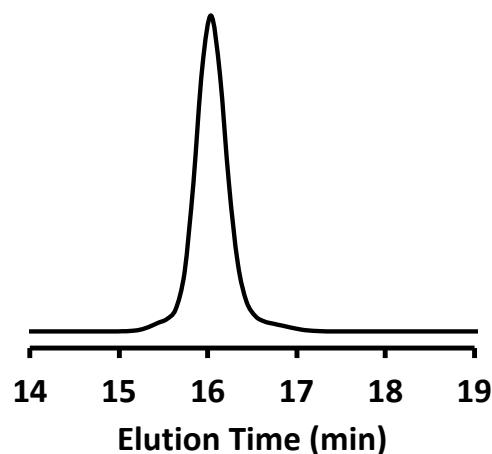


Fig. S14 SEC chromatogram of PS-(OH)₂-PMMA.

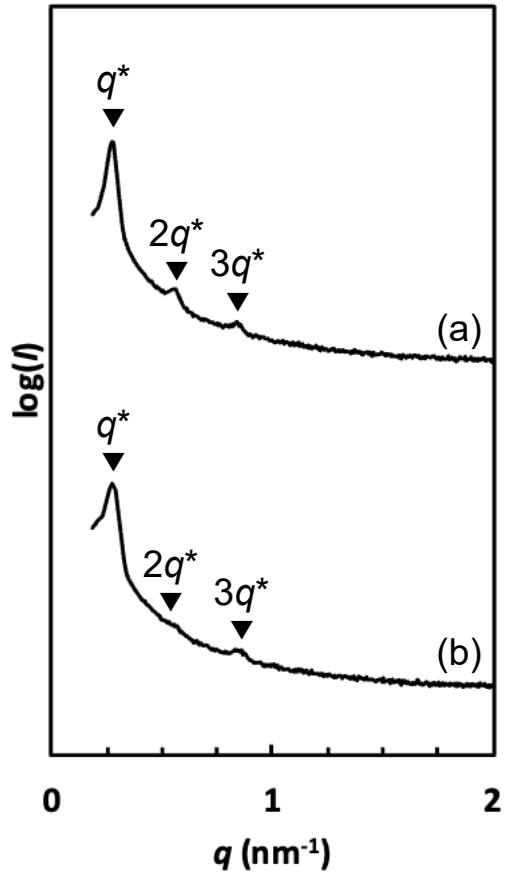


Fig. S15 1D SAXS profiles of (a) PS-(OTBS)₂-PMMA and (b) PS-(OH)₂-PMMA.

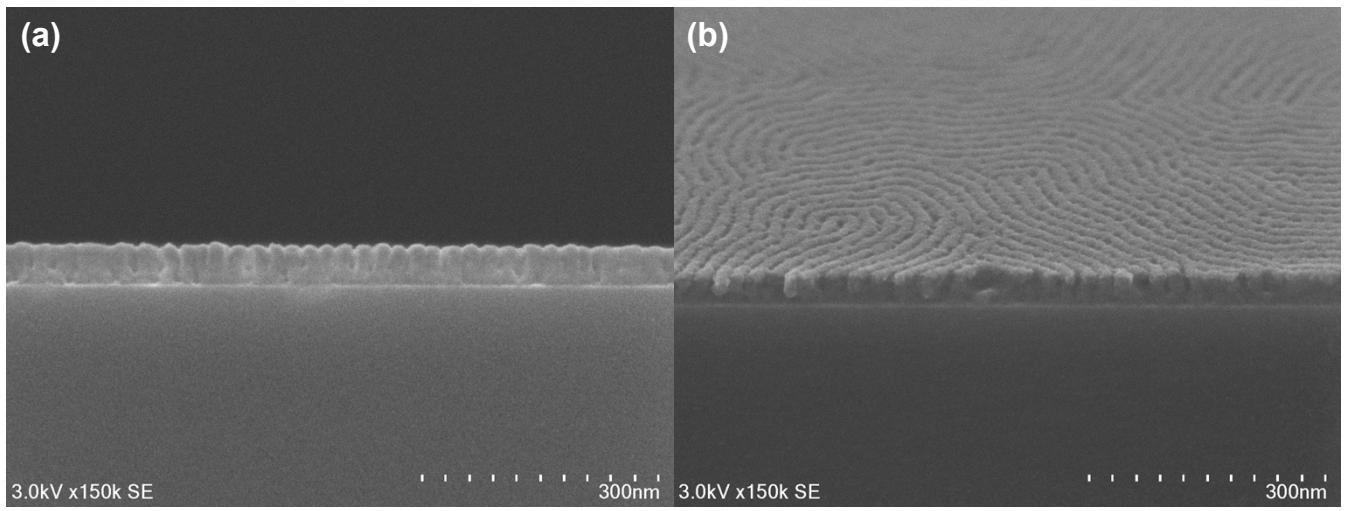


Fig. S16 (a) Cross-sectional and (b) tilted FE-SEM images of a PS-(OH)₂-PMMA thin film applied onto a PS-(OH)₂-PMMA neutral layer, which were annealed for 20 minutes. Both images were taken without the etching of PMMA domains.

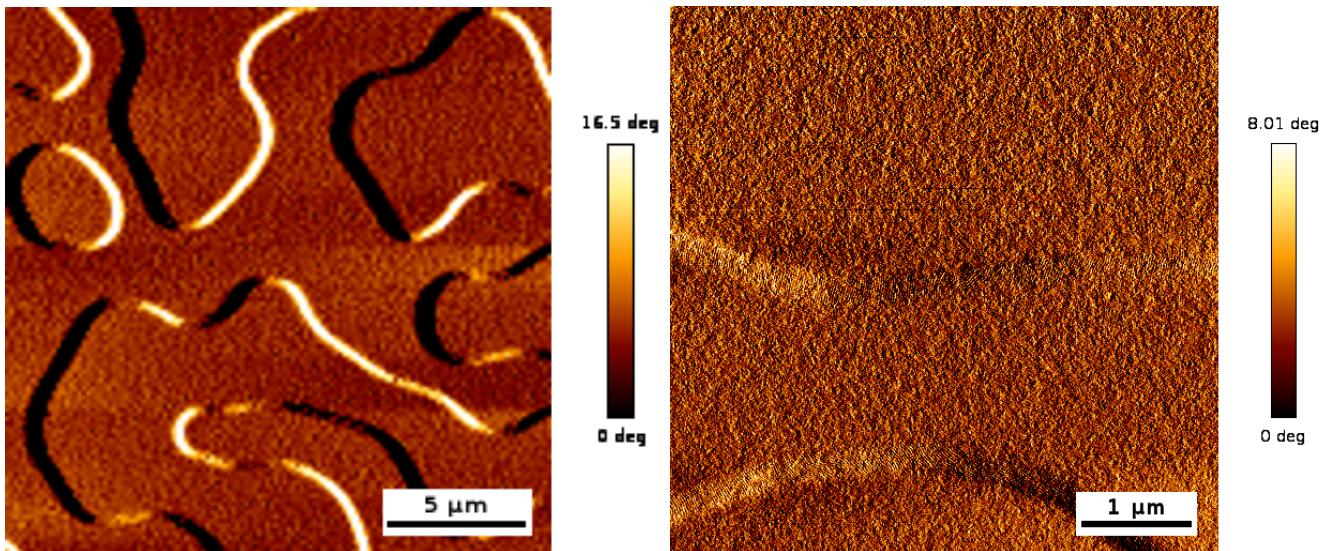


Fig. S17 AFM phase images (20 μm square, left, and 5 μm square, right) of PS-(OH)₂-PMMA thin films (~ 30 nm) applied onto a PS-(OTBS)₂-PMMA neutral layer annealed for 30 minutes, exhibiting parallel orientation of lamellae.

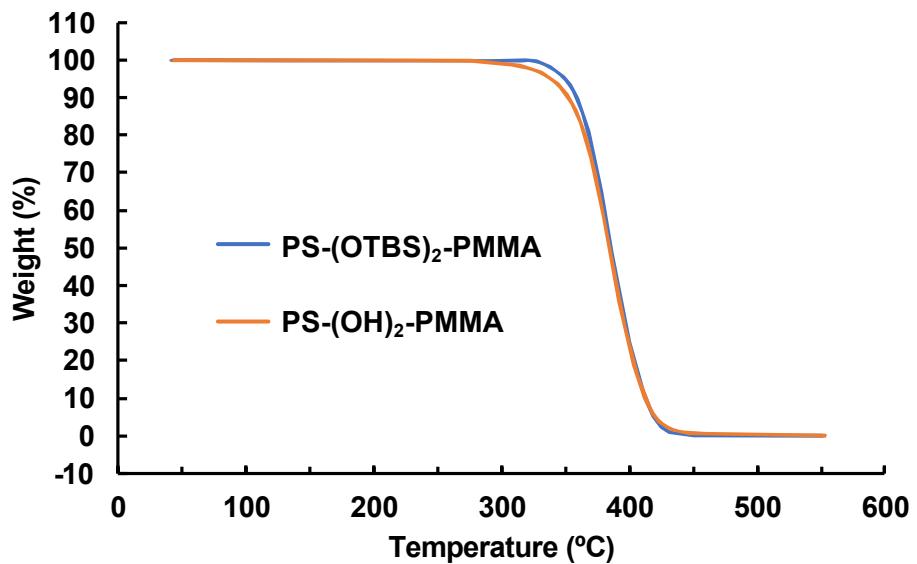


Fig. S18 TG curves of PS-(OTBS)₂-PMMA (blue line) and PS-(OH)₂-PMMA (orange line). 5% weight loss temperatures are 350°C and 339°C , respectively.

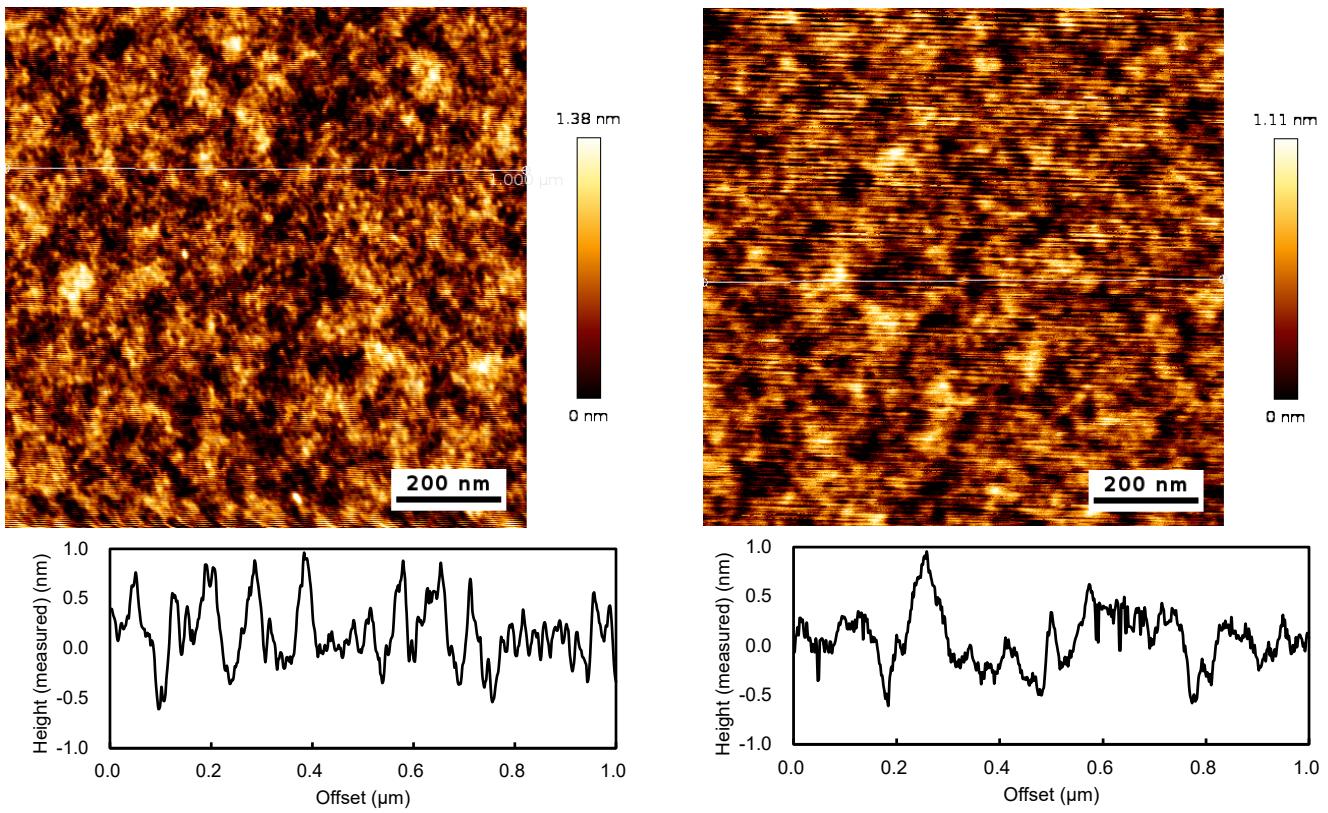


Fig. S19 AFM height images of PS-(OH)₂-PMMA neutral layers annealed for 1 minute (~ 6 nm, left) and 30 minutes (~ 8 nm, right), accompanied by the cross-sectional height profiles (taken from the white line in the images) below. The values of root-mean-square surface roughness of each NLs are 0.31 nm and 0.28 nm, respectively.

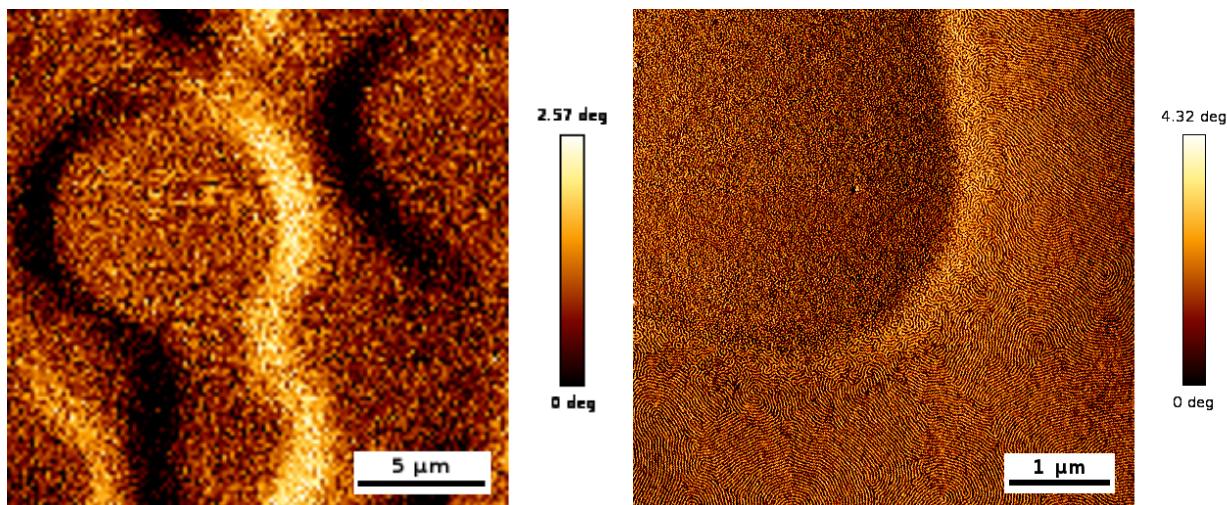


Fig. S20 AFM phase images of a PS-(OH)₂-PMMA thin film that were directly cast onto a Si substrate and annealed at 250°C for 30 minutes (~ 40 nm). Perpendicular orientation of lamellae was only partly observed.

References

- 1 J. Wu, S. Bo, J. Liu, T. Zhou, H. Xiao, L. Qiu, Z. Zhen and X. Liu, *Chem. Commun.*, 2012, **48**, 9637-9639.